

ABSTRACT

Ground Contact Of An Integrated Circuit Testing Apparatus

A ground electrical contact for an integrated circuit (IC) testing apparatus that
5 comprises: a rigid bottom member having two planar surfaces that slope
towards each other, so that the bottom member forms a partial wedge shape
with the top end of the wedge being narrower than the bottom end; a flexible
top member having two arms extending over said bottom member such that
the top member forms an inverted U-shape, said two arms having an inwards
10 bias such that an inner surface of each arm is pressed in contact with each
planar surface; and a compressible member located between the narrower
end of said bottom member and a bifurcation inner surface, which is an inner
surface where the two arms bifurcate in the top member. The bottom member
and top member are made of an electrically conductive material.

15

Figure 1